

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OHNO ET AL.	
		10/585,638	Examiner	Art Unit JONATHAN HAN
				4176 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,103,315 A	07-1978	Hempstead et al.	257/E43.004
*	B	US-5,294,287 A	03-1994	Chang et al.	438/918
*	C	US-5,390,061 A	02-1995	Nakatani et al.	257/E43.004
*	D	US-5,734,605 A	03-1998	Zhu et al.	257/E21.665
*	E	US-5,768,181 A	06-1998	Zhu et al.	365/158
*	F	US-2001/0007532 A1	07-2001	Sato et al.	365/173
*	G	US-6,456,467 B1	09-2002	Mao et al.	360/319
*	H	US-2003/0209770 A1	11-2003	Flatte et al.	257/421
*	I	US-6,713,195 B2	03-2004	Wang et al.	257/E43.005
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.